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Components, Packaging, and Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on] , Volume: 19 , Issue: 2 , March 1996

Pages:361 - 371

[\[Abstract\]](#) [\[PDF Full-Text \(936 KB\)\]](#) IEEE JNL**2 Emulation and enhancement of the Honeywell 2600 automatic test station***Wenzel, D.; Dichert, R.; Tse, M.;*

AUTOTESTCON '99. IEEE Systems Readiness Technology Conference, 1999. IEEE , 30 Aug.-2 Sept. 1999

Pages:439 - 450

[\[Abstract\]](#) [\[PDF Full-Text \(796 KB\)\]](#) IEEE CNF**3 Error recovery using forced validity assisted by executable assertions for error detection: an experimental evaluation***Hiller, M.;*

EUROMICRO Conference, 1999. Proceedings. 25th , Volume: 2 , 8-10 Sept. 1999. Pages:105 - 112 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(84 KB\)\]](#) IEEE CNF**4 The PURE family of object-oriented operating systems for deeply**

embedded systems

Beuche, D.; Guerrouat, A.; Papajewski, H.; Schroder-Preikschat, W.; Spinczyk, U.;

Object-Oriented Real-Time Distributed Computing, 1999. (ISORC '99) Proceed
2nd IEEE International Symposium on , 2-5 May 1999

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